M H H O H M	0	0	0	0	0	0	0
r Definition							
S t p e p p O C Error							
O O H H O H P O		ļ					
Time Stamp	2003/11/19 08:28	2003/11/19 08:28	2003/11/19 08:28	2003/11/19 08:29	2003/11/19 09:20	2003/11/19 09:36	2003/11/19 09:40
DBs	USPAT; US-PGPUB	USPAT; US-PGPUB	EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB	SPAT; 3-PGPUB	EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB
Search Text	Fazzano-Nicholas-G.in. and @pd>20030613	Fazzano-Nicholas.in. and @pd>20030613	Fazzano-N.in. and @pd>20030613	cls.	cellation voicead\$3 imag\$3 pmera ccd (charalotto lotter voucher\$1 pasheat\$3 thermaa\$4 IR UV infrht) and @pd>20	el\$4 cancellation void\$3 valid\$5) scan\$4 read\$3 imag\$3 picture uph\$2 camera ccd (charge adj1 ) near5 (lotto lottery lotteries card\$1 voucher\$1 pass)) near5 mark\$3 heat\$3 thermal\$2 \$2 radia\$4 IR UV infrared	((lotto lottery) adj2 (ticket\$1 card\$1)) near5 (read\$3 scan\$4 imag\$3) and @pd>20030613
Hi ts	0	0	0	529	18	Н	14
Туре	BRS	BRS	BRS	BRS	BRS	BRS	BRS
	31	32	33	34	35	36	37

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Error Definition						
C O H H O H P N						1
Time Stamp	2003/11/19 09:48	2003/11/19 09:51	2003/11/19 09:52	2003/11/19 09:52	2003/11/19 09:52	2003/11/19 09:53
DBs	EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB	USPAT; US-PGPUB	EPO; JPO; DERWENT; IBM_TDB	EPO; JPO; DERWENT; IBM_TDB	USPAT; and US-PGPUB
Search Text		cel\$4 and	cel\$4 iat\$3	(lotto lottery ticket\$1) near5 (cancel\$4 cancellation void\$3 valid\$5) near5 (thermal\$2 heat\$3 radiat\$3 light uv ultraviolet ir infrared chemical\$2) and @pd>20030613	ttery ticket\$1) near5 (cancel\$4 ion void\$3 valid\$5 brand\$3 ear5 (thermal\$2 heat\$3 radiat\$3 ultraviolet ir infrared 2) near5 (print\$3) and 613	(cancel\$4 cancellation void\$3 valid\$5 brand\$3) near5 (thermal\$2 heat\$3 radiat\$3 light uv ultraviolet ir infrared chemical\$2) near5 (print\$3) and @pd>20030613
Hits	7	ю	0	0	0	16
Туре	BRS	BRS	BRS	BRS	BRS	BRS
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Error D finition					
CO H H O H P W					
Time Stamp	2003/11/19 09:58	2003/11/19 09:58	2003/11/19 09:58	2003/11/19 10:28	2003/11/19 10:29
DBs	EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB	EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB	USPAT; US-PGPUB
Search Text	el\$4 cancellation void\$3 valid\$5 \$3) near5 (thermal\$2 heat\$3 :\$3 light uv ultraviolet ir red chemical\$2) near5 (print\$3) and	(lotto lottery game) near3 ticket\$1 near5 refund\$3 and @pd>20030613	game) near3 ticket\$1 and @pd>20030613	58/1.12.ccls. not (273/138.1.ccls. 63/16.ccls. 463/17.ccls. 101/483.ccls. 35/493.ccls. 235/375.ccls. 35/380.ccls. 235/381.ccls. 35/454.ccls. 235/487.ccls.)	382/187.ccls. not (358/1.12.ccls. 273/138.1.ccls. 463/16.ccls. 463/17.ccls. 101/483.ccls. 235/493.ccls. 235/375.ccls. 235/380.ccls. 235/381.ccls. 235/454.ccls. 235/487.ccls.)
Hits	0	0	0	327	
TYP	BRS	BRS	BRS	BRS	
	44	45	46	47	48

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